Product data sheet

1. General description

Planar passivated sensitive gate four quadrant triac in a SOT223 surface-mountable plastic package intended for applications requiring direct interfacing to logic level ICs and low power gate drivers.

2. Features and benefits

- · Direct interfacing to logic level ICs
- · Direct interfacing to low power gate drive circuits
- High blocking voltage capability
- · Planar passivated for voltage ruggedness and reliability
- Sensitive gate in four quadrants
- · Surface-mountable package
- · Triggering in all four quadrants

3. Applications

- General purpose low power motor control
- Home appliances
- Industrial process control
- Low power AC Fan controllers

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Absolute	maximum rating						
V_{DRM}	repetitive peak off-state voltage			-	-	800	V
I _{T(RMS)}	RMS on-state current	RMS on-state current full sine wave; T _{sp} ≤ 105 °C; Fig. 1; Fig. 2; Fig. 3		-	-	1	А
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5		-	-	8	А
		full sine wave; $T_{j(init)} = 25 ^{\circ}\text{C}$; $t_p = 16.7 \text{ms}$		-	-	8.5	Α
T _j	junction temperature			-	-	125	°C
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static ch	aracteristics						
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G+;$ $T_j = 25 \text{ °C; } Fig. 9$		-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 9$		-	-	10	mA

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Symbol	Parameter	Conditions		Min	Тур	Max	Unit	
Static cha	Static characteristics							
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{ G-};$ $T_j = 25 ^{\circ}\text{C}; \underline{\text{Fig. 9}}$		-	-	10	mA	
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- G+; $ $T_j = 25 \text{ °C}; Fig. 9$		-	-	10	mA	
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 11</u>		-	-	10	mA	
V _T	on-state voltage	I _T = 1.4 A; T _j = 25 °C; <u>Fig. 12</u>		-	1.3	1.6	V	
Dynamic	characteristics							
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 110 °C; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 14		50	-	-	V/µs	
dV _{com} /dt	rate of change of commutating voltage	$V_D = 400 \text{ V}; T_j = 110 ^{\circ}\text{C};$ $dI_{com}/dt = 0.44 \text{ A/ms}; \text{ gate open circuit}$		2	-	-	V/µs	

5. Pinning information

Table 2. Pinning information

Symbol	Description	Simplified outline	Graphic symbol
T1	main terminal 1	4	N
T2	main terminal 2		T2 T1
G	gate		sym051
T2	main terminal 2		
	T1 T2 G	T1 main terminal 1 T2 main terminal 2 G gate	T1 main terminal 1 T2 main terminal 2 G gate

6. Ordering information

Table 3. Ordering information

table of ordering information									
Type number	Package	Orderable part number	Packing	Small packing	Package	Package			
	Name		method	quantity	version	issue date			
Z0109NN	SOT223	Z0109NN,135	Reel	4000	SOT223	16-Mar-2006			

7. Marking

Table 4. Marking codes

Type number	Marking codes
Z0109NN	0109NN

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8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	800	V
I _{T(RMS)}	RMS on-state current	full sine wave; $T_{sp} \le 105 ^{\circ}\text{C}$; Fig 1; Fig 2; Fig 3	-	1	А
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig 4; Fig 5	-	8	А
		full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms	-	8.5	Α
l ² t	I ² t for fusing	t _p = 10 ms; SIN	-	0.32	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 20 mA; T2+ G+	-	50	A/µs
		I _G = 20 mA; T2- G+	-	50	A/µs
		I _G = 20 mA; T2- G-	-	50	A/µs
		I _G = 20 mA; T2- G+	-	20	A/µs
I _{GM}	peak gate current		-	1	А
P_{GM}	peak gate power		-	2	W
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.1	W
T _{stg}	storage temperature		-40	150	°C
T _j	junction temperature		-	125	°C

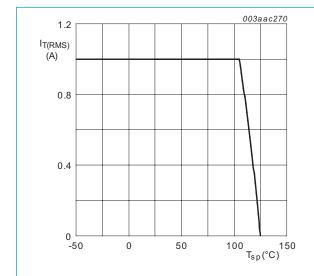
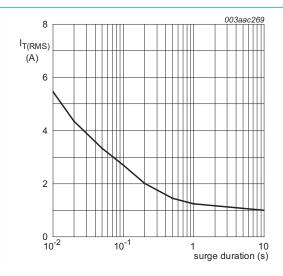
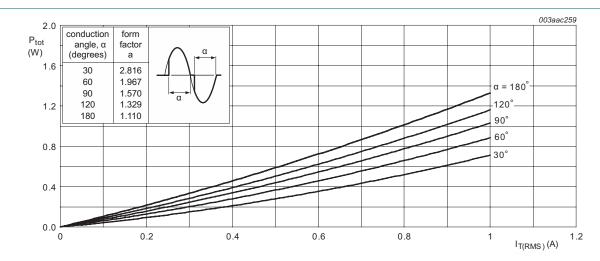


Fig. 1. RMS on-state current as a function of Solder point temperature; maximum values



f = 50 Hz; T_{sp} = 105 °C Fig. 2. RMS on-state current as a function of surge duration; maximum values

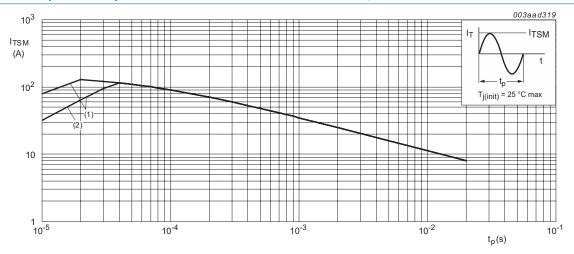
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 α = conduction angle

a = form factor = $I_{T(RMS)}$ / $I_{T(AV)}$

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

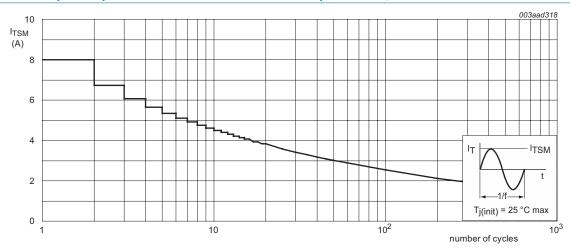


t_p ≤ 20 ms

(1) dI_T/dt limit

(2) T2- G+ quadrant limit

Non-repetitive peak on-state current as a function of pulse width; maximum values



f = 50 Hz

Z0109NN

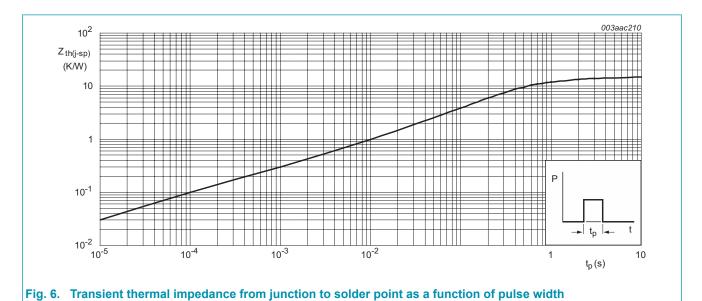
Fig. 5. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum All information provided in this document is subject to legal disclaimers.

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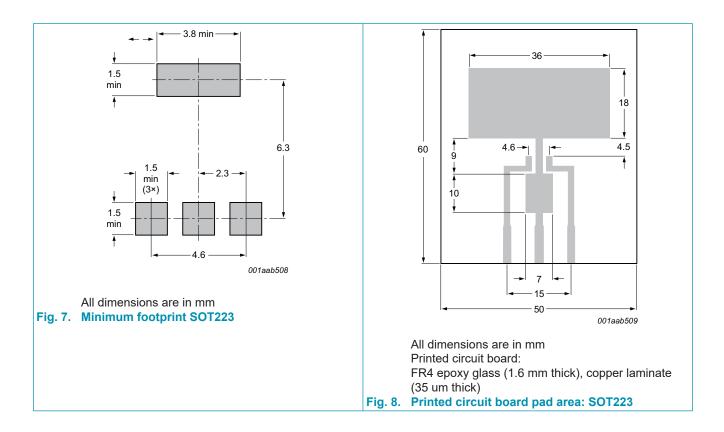
9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-sp)}}$	thermal resistance from junction to solder point	full cycle; Fig 6	-	-	15	K/W
R _{th(j-a)}	thermal resistance from junction to	full cycle; printed circuit board mounted; minimum footprint; Fig 7	-	156	-	K/W
	ambient	full cycle; printed circuit board mounted; pad area; Fig 8	-	70	-	K/W



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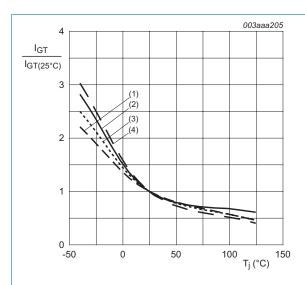


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10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 9$	-	-	10	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 9$	-	-	10	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{G-};$ $T_j = 25 \text{ °C}; Fig. 9$	-	-	10	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- G+;$ $T_j = 25 \text{ °C}; Fig. 9$	-	-	10	mA
l _L	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 10$	-	-	15	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 10$	-	-	25	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \underline{\text{Fig. 10}}$	-	-	15	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G+};$ $T_j = 25 \text{ °C}; \underline{\text{Fig. 10}}$	-	-	15	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 11</u>	-	-	10	mA
V _T	on-state voltage	I _T = 1.4 A; T _j = 25 °C; <u>Fig. 12</u>	-	1.3	1.6	V
V_{GT}	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 13	-	-	1	V
		V _D = 400 V; I _T = 0.1 A; T _j = 125 °C	0.2	-	-	V
I _D	off-state current	V _D = 800 V; T _j = 125 °C	-	-	0.5	mA
Dynamic	characteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_{j} = 110 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 14	50	-	-	V/µs
dV _{com} /dt	rate of change of commutating voltage	$V_D = 400 \text{ V}; T_j = 110 \text{ °C};$ $dI_{com}/dt = 0.44 \text{ A/ms}; \text{ gate open circuit}$	2	-	-	V/µs





- (2) T2- G-
- (3) T2+ G-
- (4) T2+ G+

Fig. 9. Normalized gate trigger current as a function of junction temperature

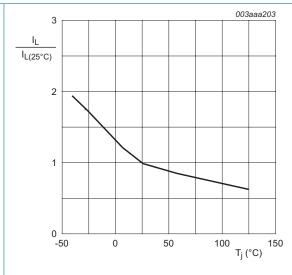


Fig. 10. Normalized latching current as a function of junction temperature

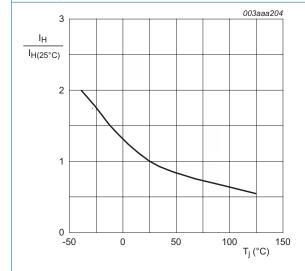
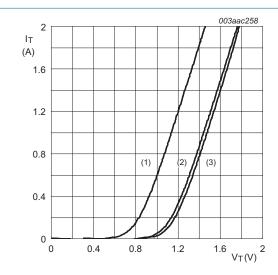


Fig. 11. Normalized holding current as a function of junction temperature



 $V_0 = 1.13 \text{ V}; R_s = 0.31 \Omega$

(1) T_j = 125 °C; typical values (2) T_j = 125 °C; maximum values

(3) T_i = 25 °C; maximum values

Fig. 12. On-state current as a function of on-state voltage

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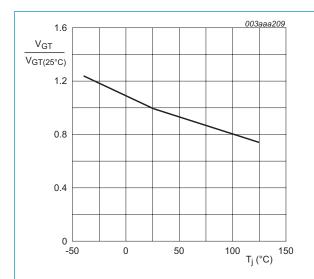


Fig. 13. Normalized gate trigger voltage as a function of junction temperature

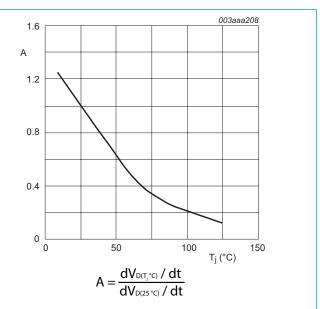
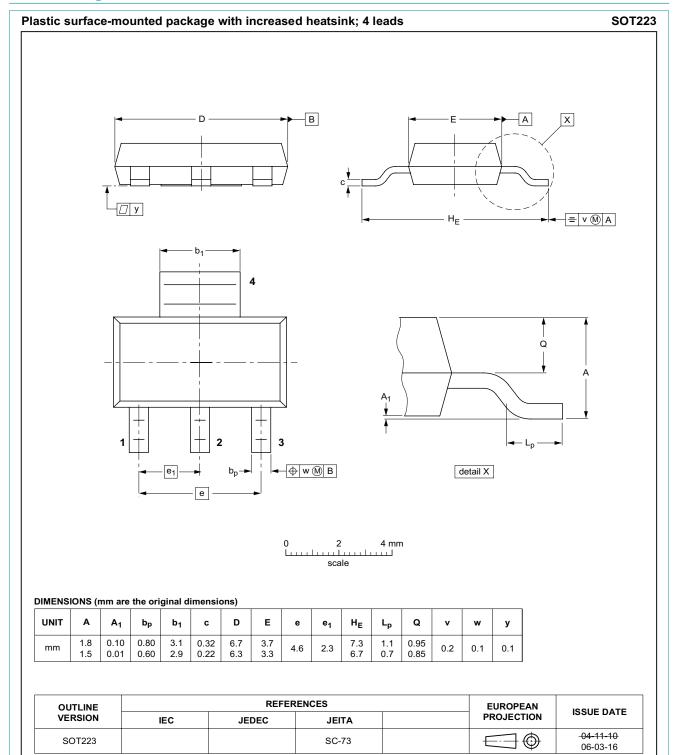


Fig. 14. Normalized critical rate of rise of off-state voltage as a function of junction temperature; typical values

11. Package outline



PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.

12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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